

Search Notes

Application/Control No.

10/506,689

Examiner

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Applicant(s)/Patent under
Reexamination

NIWANO, KAZUHITO

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
370	347	4/14/2007	IAK
370	331	4/14/2007	IAK
455	442	4/14/2007	IAK
455	10	4/14/2007	IAK
455	13.4	4/14/2007	IAK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EASTImage and keyword search in USPAT, US-PGPUB, DERWENT, EPO, IBM_TDB (see attached search strategy)	4/14/2007	IAK